



Examination of refractive record evaluated Antireflection Coating on Silicon Substrate for Solar cell Application

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ABSTRACT Show work goes for the portrayal of ARC films in the noticeable range, up to five layers antireflection covering film were composed and recreated, optical reflection esteems were derived with a Transfer Matrix Method definition (TMM). Six materials including nanoporous material have been chosen to explore the ideal estimations of the Anti-reflection covering (ARC) film for sun based cells. The present work has been completed to examine the ideal estimations of reflectance as an element of wavelength in the obvious area. The reflectance has been decreased from 32% of the silicon surface to less than 1% utilizing multilayer ARC film. It has been watched that by expanding the quantity of layers the normal reflectance diminishes over a wide scope of unmistakable range.

KEYWORD: ANTIREFLECTION COATING (ARC), REFLECTANCE, TRANSFER MATRIX METHOD, DOUBLE LAYER, THREE LAYERS, FOUR LAYERS, FIVE LAYERS.